

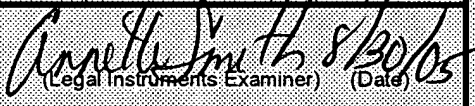


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/015,033	CHUNG, MICHAEL S.C.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
327	131			327	540	170				
INTERNATIONAL CLASSIFICATION										
H	0	3	K	4106						
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HIEP NGUYEN 08.25.05 (Assistant Examiner) / (Date)				 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)				Total Claims Allowed: 14		
 (Legal Instruments Examiner) (Date)				8/30/05 (Date)				O.G. Print Claim(s) 1	O.G. Print Fig 1	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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